

Confusion matrix for two possible outcomes p (positive) and n (negative)

		Actual		Total
		p	n	
Predicted	p'	true positive	false positive	P
	n'	false negative	true negative	N
total		P'	N'	

Classification accuracy
 $(TP + TN) / (TP + TN + FP + FN)$

Error rate
 $(FP + FN) / (TP + TN + FP + FN)$

Paired criteria

Precision: (or Positive predictive value) proportion of predicted positives which are actual positive
 $TP / (TP + FP)$

Recall: proportion of actual positives which are predicted positive
 $TP / (TP + FN)$

Sensitivity: proportion of actual positives which are predicted positive
 $TP / (TP + FN)$

Specificity: proportion of actual negative which are predicted negative
 $TN / (TN + FP)$

True positive rate: proportion of actual positives which are predicted positive
 $TP / (TP + FN)$

True negative rate: proportion of actual negative which are predicted negative
 $TN / (TN + FP)$

Positive likelihood: likelihood that a predicted positive is an actual positive
 $sensitivity / (1 - specificity)$

Negative likelihood: likelihood that a predicted negative is an actual negative
 $(1 - sensitivity) / specificity$

Combined criteria

BCR: Balanced Classification Rate
 $\frac{1}{2} (TP / (TP + FN) + TN / (TN + FP))$

BER: Balanced Error Rate, or **HTER:** Half Total Error Rate: $1 - BCR$

F-measure harmonic mean between precision and recall
 $2 (precision \cdot recall) / (precision + recall)$

F₁-measure weighted harmonic mean between precision and recall
 $(1+P)^2 TP / ((1+P)^2 TP + P^2 FN + FP)$

The harmonic mean between specificity and sensitivity is also often used and sometimes referred to as F-measure.

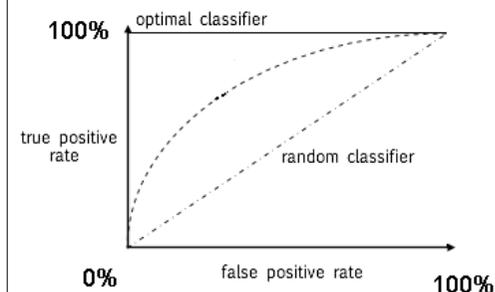
Youden's index: arithmetic mean between sensitivity and specificity
 $sensitivity - (1 - specificity)$

Matthews correlation correlation between the actual and predicted
 $((TP \cdot TN - FP \cdot FN) / ((TP+FP) (TP+FN) (TP + FP) (TN+FN)))^{1/2}$
 comprised between -1 and 1

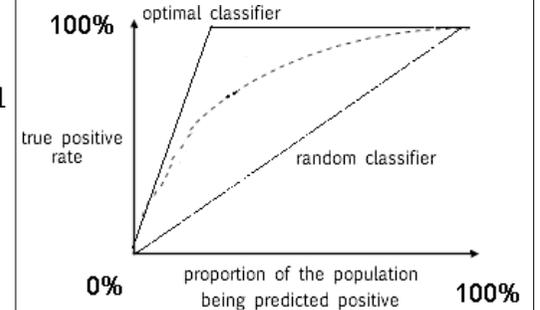
Discriminant power normalised likelihood index
 $\sqrt{3} / \sqrt{J}$
 $(\log (sensitivity / (1 - specificity)) + \log (specificity / (1 - sensitivity)))$
 $<1 = poor, >3 = good, fair otherwise$

Graphical tools

ROC curve receiver operating characteristic curve : 2-D curve parametrized by one parameter of the classification algorithm, e.g. some threshold in the « true positive rate / false positive rate » space
AUC The area under the ROC is between 0 and 1



(Cumulative) Lift chart plot of the true positive rate as a function of the proportion of the population being predicted positive, controlled by some classifier parameter (e.g. a threshold)



Relationships

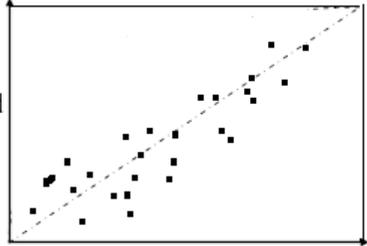
sensitivity = recall = true positive rate
 specificity = true negative rate
 $BCR = \frac{1}{2} \cdot (sensitivity + specificity)$
 $BCR = 2 \cdot Youden's\ index - 1$
 $F\text{-measure} = F_1\text{measure}$
 $Accuracy = 1 - error\ rate$

References

Sokolova, M. and Lapalme, G. 2009. A systematic analysis of performance measures for classification tasks. Inf. Process. Manage. 45, 4 (Jul. 2009), 427-437.
 Demsar, J.: Statistical comparisons of classifiers over multiple data sets. Journal of Machine Learning Research 7 (2006) 1-30

Regression performances measure cheat sheet

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<p>Let $D = \{(x_i, y_i)\}$ be a set of input/output pairs and f a function such that for $i = 1..n$,</p> $y_i = f(x_i) + \epsilon_i$	<p>Absolute error</p> <p>MAD Mean Absolute Deviation $\frac{1}{n} \sum \epsilon_i$</p> <p>MAPE Mean Absolute Percentage Error $\frac{1}{n} \sum_i \frac{ \epsilon_i }{y_i}$</p>	<p>Robust error measures</p> <p>Median Squared error $median(\epsilon_i^2)$</p> <p>α-trimmed MSE $\frac{1}{\#I} \sum_{i \in I} \epsilon_i^2$</p> <p>where I is the set of residuals ϵ_i where α percents of the largest values are discarded.</p> <p>M-estimators $\frac{1}{n} \sum_i \rho(\epsilon_i)$</p> <p>where ρ is a non-negative function with a minimum in 0, like the parabola, the Hubber function, or the bisquare function.</p>	<p>Resampling methods</p> <p>LOO - Leave-one-out: build the model on $n - 1$ data elements and test on the remaining one. Iterate n times to collect all ϵ_i and compute mean error.</p> <p>X-Val - Cross validation. Randomly split the data in two parts, use the first one to build the model and the second one to test it. Iterate to get a distribution of the test error of the model.</p> <p>K-Fold - Cut the data into K parts. Build the model on the K-1 first parts and test on the Kth one. Iterate from 1 to K to get a distribution of the test error of the model.</p> <p>Bootstrap - Draw a random subsample of the data with replacement. Compute the error on the whole dataset minus the training error of the model and iterate to get a distribution of such values. The mean of the distribution is the optimism. The bootstrap error estimate is the training error on the whole dataset plus the optimism.</p>
<p>Squared error</p> <p>SSE Sum of Squared Errors, or RSS Residual Sum of Squares $\sum_i \epsilon_i^2$</p> <p>MSE Mean Squared Error $\frac{1}{n} \sum_i \epsilon_i^2$</p> <p>RMSE Root Mean Squared Error $\sqrt{\frac{1}{n} \sum_i \epsilon_i^2}$</p> <p>NMSE Normalised Mean Squared Error $\frac{SSE}{var(\{y_i\})}$</p> <p>where var is the empirical variance in the sample.</p> <p>R-squared $1 - \frac{SSE}{var(y_i)}$</p> <p>where var is the empirical variance in the sample</p>	<p>Predicted error</p> <p>PRESS Predicted REsidual Sums of Squares $\frac{1}{n} \ diag(XX^T)(XX^T - I)Y\ _2^2$ where X is a matrix built by stacking the x_i in rows. Y is the vector of y_i</p> <p>GCV Generalised Cross Validation $\frac{\frac{1}{n} \ (I - X(X^T X + nI)^{-1} X^T)Y\ ^2}{(\frac{1}{n} Trace(I - X(X^T X + nI)^{-1} X^T))^2}$ where X is a matrix built by stacking the x_i in rows. Y is the vector of y_i</p>	<p>Graphical tool</p> <p>Plot of predicted value against actual value. A perfect model places all dots on the diagonal.</p> 	
	<p>Information criteria</p> <p>AIC Akaike Information Criterion $n \log MSE + 2k$ where k is the number of parameters in the model</p> <p>BIC Bayesian Information Criterion $n \log MSE + k \cdot \log n$ where k is the number of parameters in the model</p>		